Current-perpendicular-to-plane giant magnetoresistance in ferromagnetic semiconductor (Ga,Fe)Sb heterostructures with high Curie temperature

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Ferromagnetic semiconductors (FMSs), which show both the properties of ferromagnets and semiconductors, are needed for future low-power spintronics devices. To realize practical spin devices, both p-type and n-type FMSs which have high Curie temperature ($T_{\rm C}$) are required, but prototypical Mn-doped FMSs (In,Mn)As or (Ga,Mn)As show only p-type with $T_{\rm C} \leq 200$ K [1]. On the other hand, we have successfully grown Fe-doped FMSs; p-type (Ga,Fe)Sb with $T_{\rm C} \simeq 340$ K [2] and n-type (In,Fe)Sb with $T_{\rm C} \simeq 335$ K [3], which are promising for devices operating at room temperature. To realize practical spintronics devices, the spin-valve effect is one of the basic and necessary characteristics. We have recently demonstrated current-in-plane giant magnetoresistance (CIP-GMR) effects in (Ga,Fe)Sb heterostructures [4], but the MR ratio was less than 2%, which is very small. Further improvement of the MR, by optimizing the geometry and structure, is necessary.

In this work, we demonstrate the CPP-GMR effect in a spin-valve structure using high- T_C (Ga,Fe)Sb. Generally, the magnetoresistance (MR) ratio of CPP-GMR is larger than that of CIP-GMR, because the MR is not only caused by the spin-dependent scattering at the ferromagnetic/nonmagnetic interfaces but also by the spin-dependent density of states of the ferromagnetic layers. As shown in Fig. 1(a), the samples examined here consist of (Ga_{0.8},Fe_{0.2})Sb (50 nm, $T_C > 320$ K)/ InAs (5 nm)/ (Ga_{0.8},Fe_{0.2})Sb (40 nm, $T_C > 320$ K) grown on an n-type Si-doped InAs buffer (200 nm) and an n+InAs substrate by low temperature molecular beam epitaxy (LT-MBE). Figure 1(b) shows the MR measured at 3.5 K with a magnetic field **H** applied perpendicular to the film plane. Clear GMR of ~ 3.5% is observed, whose peaks ($\approx \pm 250$ G) agree with the coercive forces of the magnetizations of the (Ga,Fe)Sb layers observed by magnetic circular dichroism (MCD) magnetometry. Although the observed MR of 3.5 % is not high enough for practical devices, this result of the spin-valve (GMR) effect in Fe-doped FMS heterostructures is an important step for device applications of high- T_C FMSs and heterostructures. **Acknowledgements:** This work was partly supported by Grants-in-Aid for Scientific Research (Nos. 16H02095, 17H04922 and 18H05345), CREST of JST (No. JPMJCR1777), and the Spintronics Research Network of Japan.



Fig. 1. (a) Schematic sample structure and measurement geometry. (b) Magnetoresistance of a $(Ga_{0.8}, Fe_{0.2})Sb$ (50 nm)/ InAs (5 nm)/ (Ga_{0.8}, Fe_{0.2})Sb (40 nm) structure measured at 3.5 K (upper panel) and the normalized hysteresis measured by MCD in the same sample (lower panel). The magnetic field H and current I are applied perpendicular to the film plane. In (b), the red and blue curves are magnetic-field-sweep directions of – to + and + to –, respectively.

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